PCN Number:		20190318003.1					N Date:	Mar 19, 2019)	
		of ASESH as Additional Assembly and Test Site for Select SOIC Package								
Customer	Contact	t:	PCN Ma	nager	Dept	Quality Servi	ces			
Proposed	1 st Ship	Date	e: Jur	ie 19,	2019	Estimated Samp Availability:	ble	Date Pro	ovided at Sam	ple
Change Ty	ype:									
Assembly Site			Desigi		n		Wafer Bump Site			
Assembly Process					Data Sheet			Wafer Bump Material		
Assembly Materials					Part number change			Wafer Bump Process		
Mechanical Specification			L L	Test Site			Wafer Fab Site			
Packing/Shipping/Labeli			abeling		Test Process			Wafer Fab Materials		
					PC	Details		Wafer	Fab Process	
Descriptio	on of Ch	ange	•		101	Detans				
Texas Inst	ruments or select	Incor device	porateo es liste	d in th		the qualification / ct Affected" Sectio				
Assembly Site Assemb		semb	bly Site Origin		Assembly Country Code		As	Assembly Site City		
TI Malay	sia		MLA			MYS		Kuala Lur	npur	
ASES	4		ASH			CHN		Shangh	nai	
Material D	Differend	ces:	TI	Mala	vsia	ASESH		1		
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Qualification Report

Approve Date 20-Dec-2018

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

	Bata Biopia/ca					
Туре	Test Name / Condition	Duration	Qual Device: <u>TMP1075D</u>	QBS Product Reference: <u>TMP1075DGKT</u>	QBS Package Reference: <u>TLIN2029DQ1</u>	
HTOL	Life Test, 150C	300 Hours	-	3/231/0		
HAST	Biased HAST, 130C/85%RH	96 Hours	1/77/0	-	3/231/0	
UHAST	Unbiased HAST 130C/85%RH	96 Hours	1/77/0	-	3/231/0	
TC	Temperature Cycle, - 65/150C	500 Cycles	1/77/0	-	3/231/0	
HTSL	High Temp Storage Bake 170C	420 Hours	1/77/0	-	-	
HBM	ESD - HBM	4000V	-	1/3/0	-	
CDM	ESD - CDM	1500 V	1/3/0	-	-	
LU	Latch-up	(per JESD78)	-	1/6/0		
ED	Electrical Characterization	Per Datasheet Parameters	1/30/0	-	-	
WBP	Bond Pull	Wires	1/76/0	-	-	
WBS	Ball Bond Shear	Wires	1/76/0	-	-	

- QBS: Qual By Similarity

- Qual Device TMP1075D is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page" For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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